

Notice of References Cited	Application/Control No. 10/590,908		Applicant(s)/Patent Under Reexamination NAKAO ET AL.	
	Examiner QUINN HUNTER		Art Unit 2835	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,587,876 A	12-1996	O'Brien et al.	361/682
*	B	US-5,806,940 A	09-1998	Heirich, Douglas L.	312/7.2
*	C	US-6,104,451 A	08-2000	Matsuoka et al.	349/58
*	D	US-6,614,656 B1	09-2003	Huang, Gread	361/690
*	E	US-6,697,250 B2	02-2004	Kuo, Yan-Lin	361/681
*	F	US-6,807,051 B2	10-2004	Takahashi, Hitoshi	361/681
*	G	US-6,894,739 B2	05-2005	Sung et al.	349/58
*	H	US-2005/0105259 A1	05-2005	Lee et al.	361/681
*	I	US-2005/0117283 A1	06-2005	Lee et al.	361/681
*	J	US-2005/0157457 A1	07-2005	Kim, Kwey-hyun	361/681
*	K	US-7,091,665 B2	08-2006	Nomoto et al.	313/583
*	L	US-7,405,925 B2	07-2008	Sung, Ki-Hyub	361/681
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.